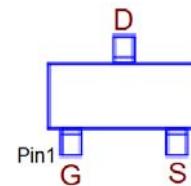
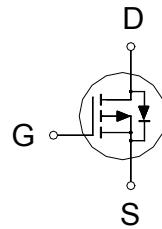


**NIKO-SEM**
**P-Channel Enhancement Mode  
Field Effect Transistor**
**PM509BA**  
**SOT-23(S)**  
**Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-30V	120mΩ	-2A

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	±20	V
Continuous Drain Current	$I_D$	-2	A
		-1.5	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	-8	
Power Dissipation	$P_D$	0.7	W
		0.4	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$		177	°C/W

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper.**ELECTRICAL CHARACTERISTICS ( $T_j = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.7	-3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			±100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V$			-1	$\mu\text{A}$
		$V_{DS} = -20V, V_{GS} = 0V, T_j = 55^\circ\text{C}$			-10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = -10V, V_{GS} = -10V$	-8			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = -4.5V, I_D = -1.5A$		134	180	$\text{m}\Omega$
		$V_{GS} = -10V, I_D = -2A$		98	120	

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Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -5V, I_D = -2A$		4.3		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$		190		pF
Output Capacitance	$C_{oss}$			36		
Reverse Transfer Capacitance	$C_{rss}$			27		
Total Gate Charge <sup>2</sup>	$Q_g$			4.8		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$	$V_{DS} = -15V, V_{GS} = -10V, I_D = -2A$		0.5		nC
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			1.3		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$			14		
Rise Time <sup>2</sup>	$t_r$			36		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$	$V_{DD} = -15V, V_{GS} = -10V$ $I_D \geq -2A, R_G = 6\Omega$		42		nS
Fall Time <sup>2</sup>	$t_f$			34		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current	$I_S$			-2	A	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = -2A, V_{GS} = 0V$		-1.1	V	
Reverse Recovery Time	$t_{rr}$	$I_F = -2A, dI_F/dt = 100A / \mu S$		15		nS
Reverse Recovery Charge	$Q_{rr}$			8		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

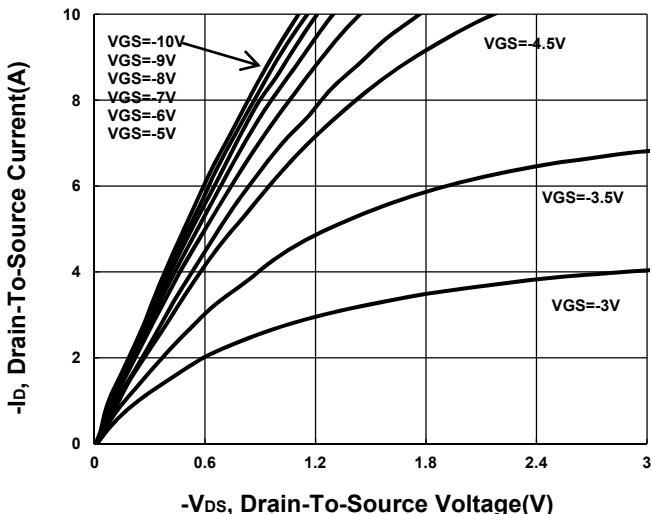
<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

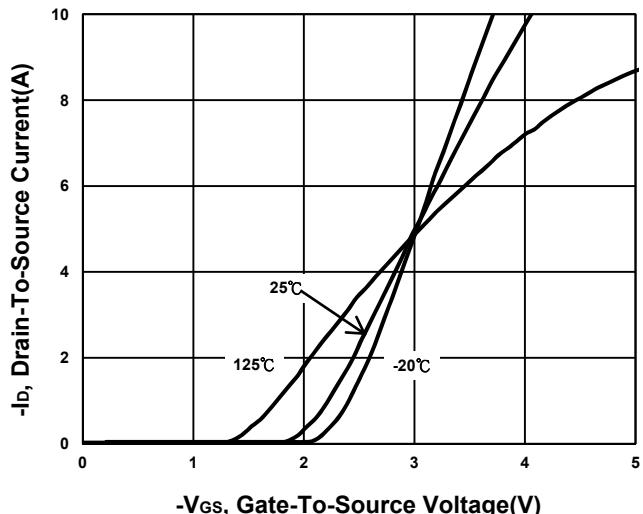
**P-Channel Enhancement Mode  
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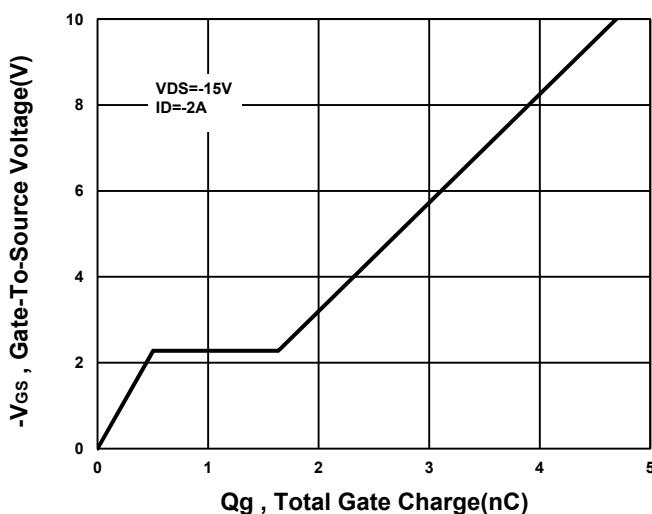
**Output Characteristics**



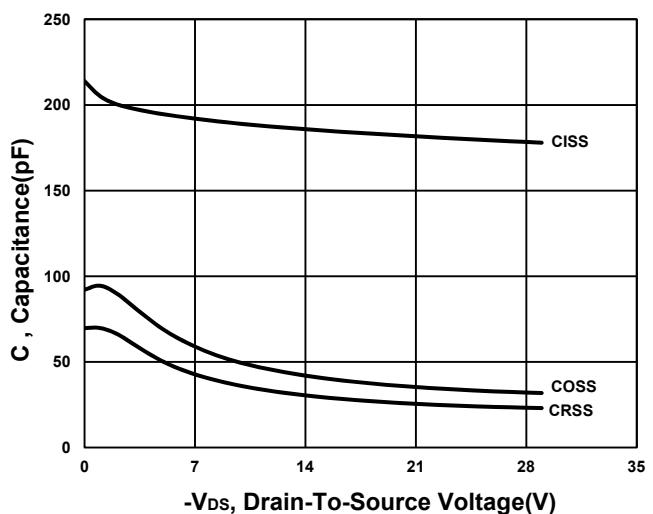
**Transfer Characteristics**



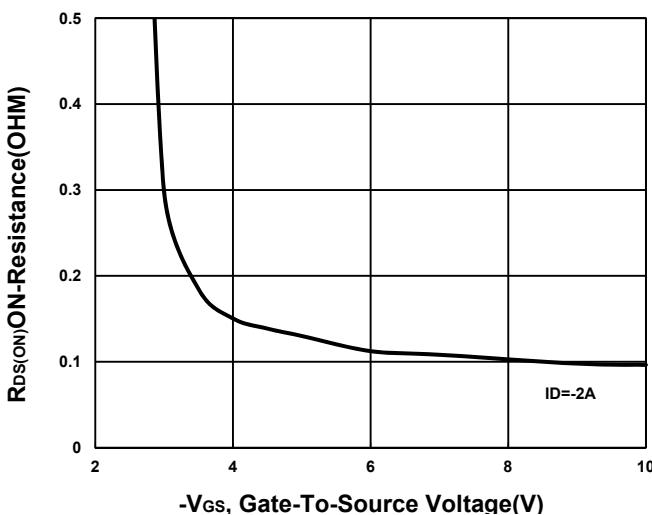
**Gate charge Characteristics**



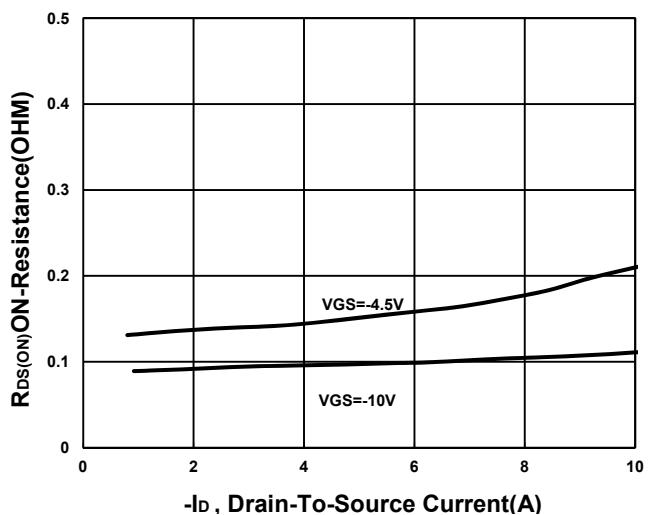
**Capacitance Characteristic**



**On-Resistance VS Gate-To-Source**



**On-Resistance VS Drain Current**



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